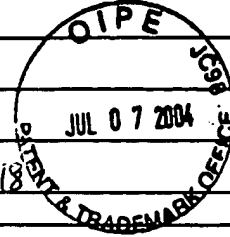


## INFORMATION DISCLOSURE CITATION

Atty. Docket No.	06720.0113	Appln. No.	10/727,550
Applicant	Ming-Dou KER et al.		
Filing Date	December 5, 2003	Group:	2835 2818



## U.S. PATENT DOCUMENTS

Examiner Initial*	Document Number	Issue Date	Name	Class	Sub Class	Filing Date If Appropriate
dh	5,744,842	4/28/1998	Ker			
dh	6,072,219	6/06/2000	Ker et al.			

## FOREIGN PATENT DOCUMENTS

Document Number	Publication Date	Country	Class	Sub Class	Translation Yes or No

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

dh	C. Duvvury and A. Amerasekera, "ESD: A pervasive reliability concern for IC technologies," <i>Proc. of IEEE</i> , vol. 81, pp. 690-702, May 1993.
dh	T.-Y Chen and M.-D. Ker, "Investigation of the gate driven effect and substrate-triggered effect on ESD robustness of CMOS devices," <i>IEEE Trans. on Device and Materials Reliability</i> , vol. 1, pp. 190-203, December 2001.

Examiner	<i>Woo</i>	Date Considered	10/16/2005
*Examiner:	Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		
Form PTO 1449		Patent and Trademark Office - U.S. Department of Commerce	